

Notice of References Cited		Application/Control No. 10/588,833	Applicant(s)/Patent Under Reexamination LIEBER ET AL.	
		Examiner DAREN WOLVERTON	Art Unit 2813	Page 1 of 1

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	C	US-			
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	L	US-			
	M	US-			

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	V	Zhang, Z. et al. "Electrically robust ultralong nanowires of NiSi, Ni ₂ Si, and Ni ₃₁ Si ₁₂ ", 24 January 2006, Applied Physics Letters 88, 043104 (2006)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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